



Sheet 1 of 1

Form 1449*

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

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Applicant: Leonard Forbes et al.

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Viet G. Nguyen

Group: 2818

Primary Examiner

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
(A)						
	_ 4,462,150	07/31/1984	Nishimura, H., et al.	29	576 B	09/16/82
	4,768,072	08/30/1988	Seki, Y., et al.	357	29	10/02/86
VV	_ 4,841,349	06/20/1989	Nakano, M.	357	30	10/28/87
	_ 5,407,845	04/18/1995	Nasu, Y., et al.	4 3\7/et	Q4lVguyen	10/13/93
M	_ 5,789,276	08/04/1998	Leas, J.M., et al.	438ns	ary Examiner	12/08/95
$\sqrt{\mathcal{L}}$	_ 6,018,166	01/25/2000	Lin, K., et al.	257	22 LAGIIIII 197	07/30/98
37	_ 6,034,001	03/07/2000	Shor, J.S., et al.	438	931	02/17/94
N	_ 6,075,259	06/13/2000	Baliga, B.J.	257	77	07/13/99
	, , ,	,	3 .			. ,
		FC	REIGN PATENT DOCUMENTS			
*Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes No

**Examiner					Translation			
Initial	Document Number	Date	Country	Class	Subclass	Yes	No	

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

Zirinsky, S., et al., "Electrical Resistivity of Amorphous Silicon Resistor Films", Extended Abstracts of the Spring Meeting of the Electrochemical Washington, DC, pp. 147-149, (May 1971)

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